

10th Anniversary "Trento" Workshop on Advanced Silicon Radiation Detectors

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SPS Test Beam characterization results with CCPDv2 and CCPDv4 capacitively coupled to FEI4

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We present the results of the characterization of CCPDV2 and CCPDV4 sensors, before and after irradiation, at the SPS using the FEI4 Telescope. The effects of bias, threshold and irradiation on the efficiency and timing properties of the CCPD family of sensors will be discussed.

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